

Introduction

This Test Interface is a hand held test clip which is designed to probe simultaneously the leads of an in-circuit IC. Terminated with a 25 way male "D" type connector, the interface makes temporary electrical contact with the leads of the device, in a two step action:

- The interface is positioned over the device to be tested (lining it up with the body of the device and the leads).
- Once it has located on the device, by gently pushing further, the high-performance probes will reach the leads of the device and make electrical contact.

Features

- achieves the best combination of reliability, repeatability, serviceability and user-friendliness;
- high contact pressure at probe tip (crown type), for repeatable and reliable contact;
- high reliability and long life probes;
- sweeping action gold plated contacts, for reliable contact and low ohmic resistance of interconnections;
- high current rating (for single channel, in ambient air with 70°F [20°C]) : 1.5A
- impact, solvent and temperature resistant plastics, with low friction;
- wide range of operating temperatures (commercial): [0°C to +70°C]
- clear markings on the body, indicating Pin 1 of IC being tested, to prevent probing the wrong way round;
- packaged in a hard wearing, high resistance to damage Polypropylene case with foam insets, the Test Interface can withstand high impact in transit.
- case can be used for safe storage when the Test Interface is not in use, and subsequent transport.



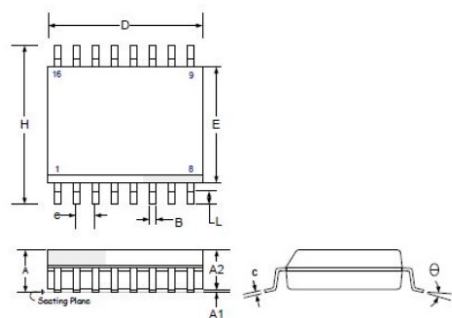
Specification

- It will accommodate 16 Pin Wide (0.3") SOIC packages - see drawing below for details
- Maximum number of interconnections (channels): 16
- Current rating, with all contacts loaded (maximum continuous current, non inductive): 0.5A /channel
- Contact resistance (average): 80 m Ω /channel
- Insulation resistance: 5M Ω Min.
- Volume resistivity of plastic parts : 10^{15} Ω -cm @ 50%RH.
- Fatigue life of probes: Min. 1,000,000 cycles at normal working distance
- Working distance (normal stroke): 1.5mm;
- Single probe force at point of contact (normal stroke): 0.16N ; at working travel: 0.7N

Connections Table

Device Pin	1	2	3	4	5	6	7	8				
Pinpoint Channel	2	4	6	8	10	12	14	16				
Device Pin	16	15	14	13	12	11	10	9				
Pinpoint Channel	1	3	5	7	9	11	13	15				

16-Pin Plastic Wide-body SOIC

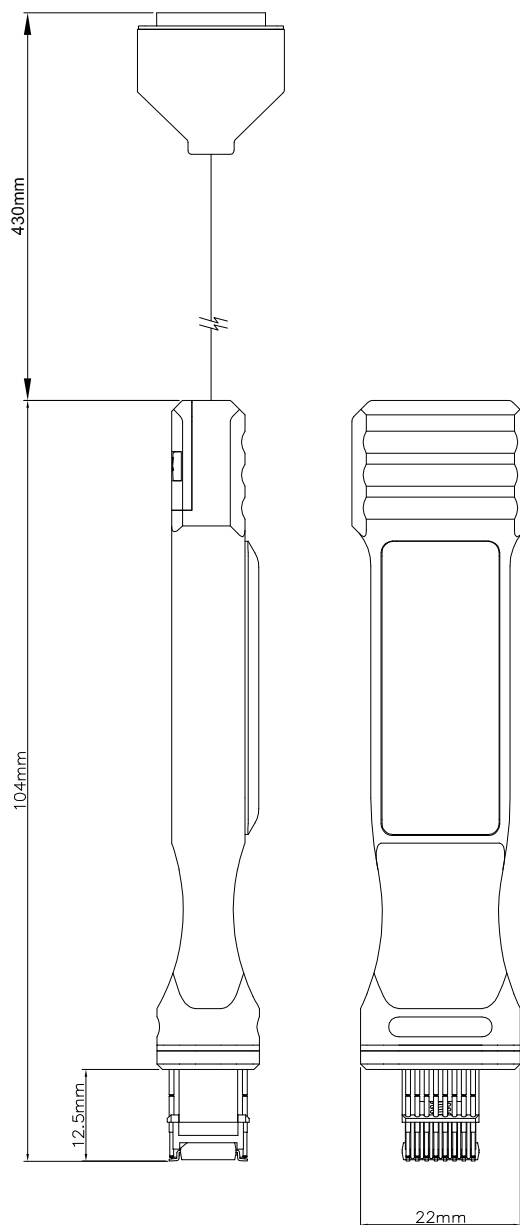


DIM	MILLIMETERS		INCHES	
	MIN	MAX	MIN	MAX
A	2.06	2.65	0.081	0.104
A1	0.10	0.30	0.004	0.012
A2	2.03	2.55	0.080	0.100
B	0.33	0.51	0.013	0.020
c	0.23	0.32	0.009	0.013
D	10.08	10.50	0.397	0.413
E	7.40	7.60	0.291	0.299
e	1.27 BSC		0.05 BSC	
H	10.00	10.65	0.394	0.419
L	0.40	1.27	0.016	0.050
Θ	0°	8°	0°	8°
*LC	-	0.10	-	0.004

Note:

1. Controlled dimensions are in mm, inches are for reference only.
2. Dimensions do not include mold flash or protrusions; these shall not exceed 0.155mm (.006") on any side. Lead dimension shall not include solder coverage.

*Lead Coplanarity



Maintenance

The Test Interface Head is maintenance free. The probes are self-cleaning. Immersion in water or contact between probes and any liquids should be avoided, as this could severely reduce the working life of probes.

Contamination is the primary cause of probe contact problems. This is generally caused by flux left as a residue on circuit boards. Other probe contaminants such as dust, fluff, oil and grime can also cause problems in other areas. Light brushing of the tips of the probes with nylon, bristle or soft metal brushes will dislodge most contaminants.